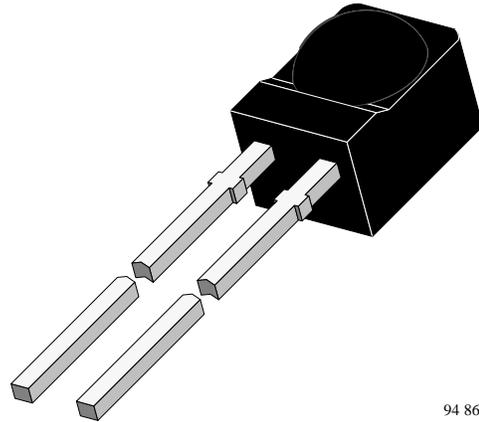

Silicon PIN Photodiode

Description

BPV23NFL is a high speed and high sensitive PIN photodiode in a plastic package with a spherical side view lens and extra long leads.

The epoxy package itself is an IR filter, spectrally matched to GaAs on GaAs and GaAlAs on GaAlAs IR emitters ($\lambda_p = 950 \text{ nm}$, $S_{rel}(\lambda = 875 \text{ nm}) > 90 \%$). Lens radius and chip position are perfectly matched to the chip size, giving high sensitivity without compromising the viewing angle.

In comparison with flat packages the spherical lens package achieves a sensitivity improvement of 80%.



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Features

- Large radiant sensitive area ($A = 5.7 \text{ mm}^2$)
- Wide viewing angle $\varphi = \pm 60^\circ$
- Improved sensitivity
- Fast response times
- Low junction capacitance
- Plastic package with universal IR filter
- Long leads for special design requirements

Applications

Infrared remote control and free air transmission systems in combination with IR emitter diodes (TSU.-, TSI.-, or TSH.-Series). High sensitivity detector for high data rate transmission systems. The IR filter matches perfectly to the high speed infrared emitters in the 830 nm to 880 nm wavelength range. This detector is optimized for infrared locking systems in automotive applications. Recommended infrared emitters are TSHA 5...-series.

Absolute Maximum Ratings

 $T_{amb} = 25^{\circ}\text{C}$

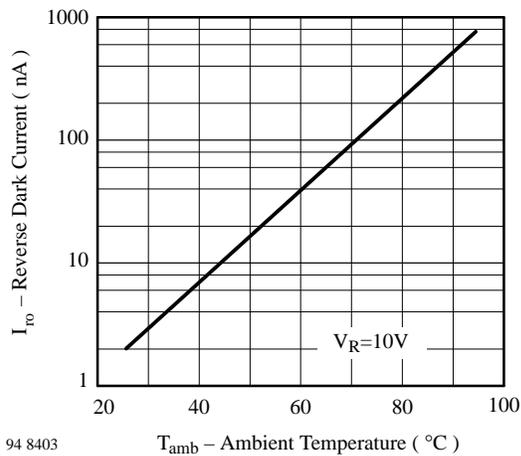
Parameter	Test Conditions	Symbol	Value	Unit
Reverse Voltage		V_R	60	V
Power Dissipation	$T_{amb} \leq 25^{\circ}\text{C}$	P_V	215	mW
Junction Temperature		T_j	100	$^{\circ}\text{C}$
Operating Temperature Range		T_{amb}	-55...+100	$^{\circ}\text{C}$
Storage Temperature Range		T_{stg}	-55...+100	$^{\circ}\text{C}$
Soldering Temperature	$t \leq 5\text{ s}$	T_{sd}	260	$^{\circ}\text{C}$
Thermal Resistance Junction/Ambient		R_{thJA}	350	K/W

Basic Characteristics

 $T_{amb} = 25^{\circ}\text{C}$

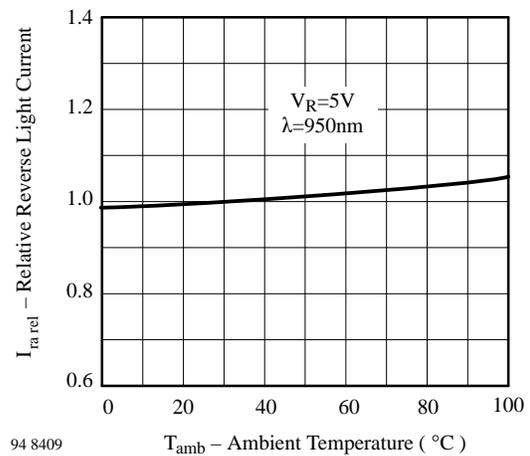
Parameter	Test Conditions	Symbol	Min	Typ	Max	Unit
Forward Voltage	$I_F = 50\text{ mA}$	V_F		1	1.3	V
Breakdown Voltage	$I_R = 100\text{ }\mu\text{A}$, $E = 0$	$V_{(BR)}$	60			V
Reverse Dark Current	$V_R = 10\text{ V}$, $E = 0$	I_{ro}		2	30	nA
Diode Capacitance	$V_R = 0\text{ V}$, $f = 1\text{ MHz}$, $E = 0$	C_D		48		pF
Serial Resistance	$V_R = 12\text{ V}$, $f = 1\text{ MHz}$	R_S		900		Ω
Open Circuit Voltage	$E_e = 1\text{ mW/cm}^2$, $\lambda = 950\text{ nm}$	V_o		390		mV
Temp. Coefficient of V_o	$E_e = 1\text{ mW/cm}^2$, $\lambda = 950\text{ nm}$	TK_{V_o}		-2.6		mV/K
Short Circuit Current	$E_e = 1\text{ mW/cm}^2$, $\lambda = 950\text{ nm}$	I_k		65		μA
Reverse Light Current	$E_e = 1\text{ mW/cm}^2$, $\lambda = 870\text{ nm}$, $V_R = 5\text{ V}$	I_{ra}	45	65		μA
Temp. Coefficient of I_{ra}	$E_e = 1\text{ mW/cm}^2$, $\lambda = 950\text{ nm}$, $V_R = 10\text{ V}$	$TK_{I_{ra}}$		0.1		%/K
Absolute Spectral Sensitivity	$V_R = 5\text{ V}$, $\lambda = 870\text{ nm}$	$s(\lambda)$		0.57		A/W
Absolute Spectral Sensitivity	$V_R = 5\text{ V}$, $\lambda = 950\text{ nm}$	$s(\lambda)$		0.60		A/W
Angle of Half Sensitivity		φ		± 60		deg
Wavelength of Peak Sensitivity		λ_p		940		nm
Range of Spectral Bandwidth		$\lambda_{0.5}$		790...1050		nm
Quantum Efficiency	$\lambda = 950\text{ nm}$	η		90		%
Noise Equivalent Power	$V_R = 10\text{ V}$, $\lambda = 950\text{ nm}$	NEP		4×10^{-14}		$\text{W}/\sqrt{\text{Hz}}$
Detectivity	$V_R = 10\text{ V}$, $\lambda = 950\text{ nm}$	D^*		5×10^{12}		$\text{cm}\sqrt{\text{Hz}}/\text{W}$
Rise Time	$V_R = 10\text{ V}$, $R_L = 1\text{ k}\Omega$, $\lambda = 820\text{ nm}$	t_r		70		ns
Fall Time	$V_R = 10\text{ V}$, $R_L = 1\text{ k}\Omega$, $\lambda = 820\text{ nm}$	t_f		70		ns
Cut-Off Frequency	$V_R = 12\text{ V}$, $R_L = 1\text{ k}\Omega$, $\lambda = 870\text{ nm}$	f_c		4		MHz
Cut-Off Frequency	$V_R = 12\text{ V}$, $R_L = 1\text{ k}\Omega$, $\lambda = 950\text{ nm}$	f_c		1		MHz

Typical Characteristics ($T_{amb} = 25^{\circ}\text{C}$ unless otherwise specified)



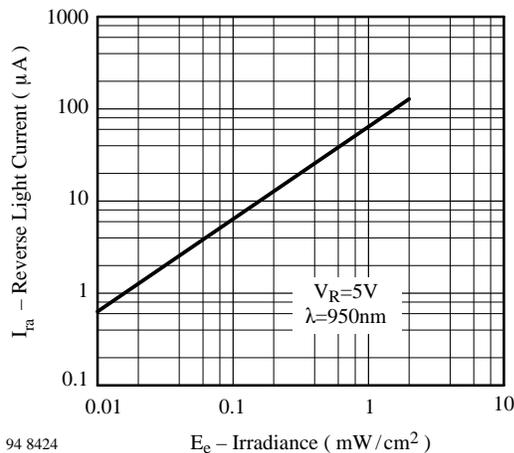
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Figure 1 : Reverse Dark Current vs. Ambient Temperature



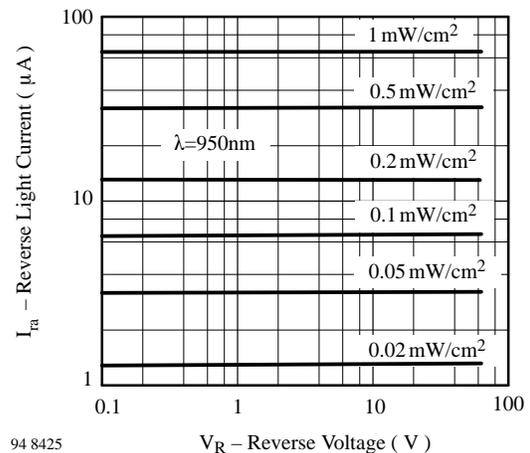
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Figure 2 : Relative Reverse Light Current vs. Ambient Temperature



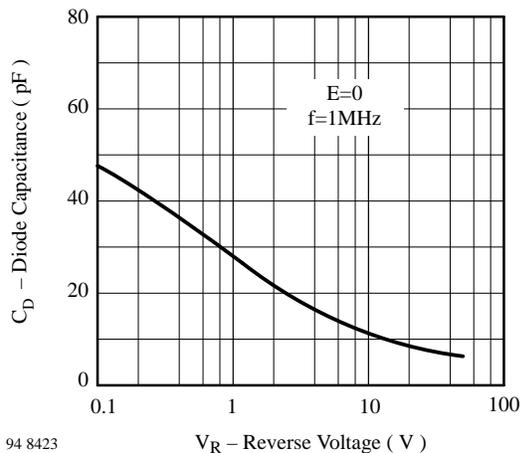
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Figure 3 : Reverse Light Current vs. Irradiance



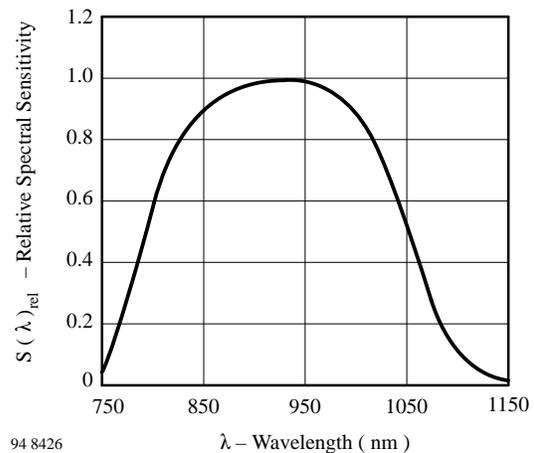
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Figure 4 : Reverse Light Current vs. Reverse Voltage



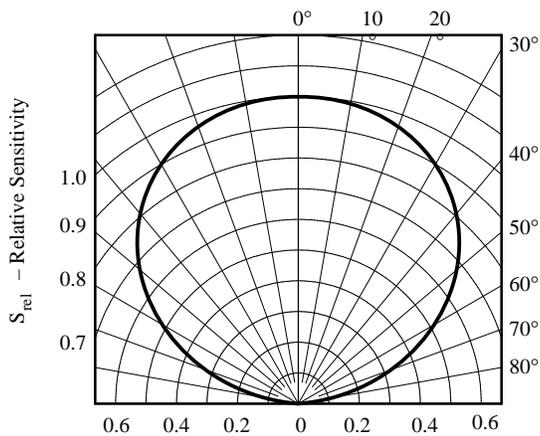
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Figure 5 : Diode Capacitance vs. Reverse Voltage



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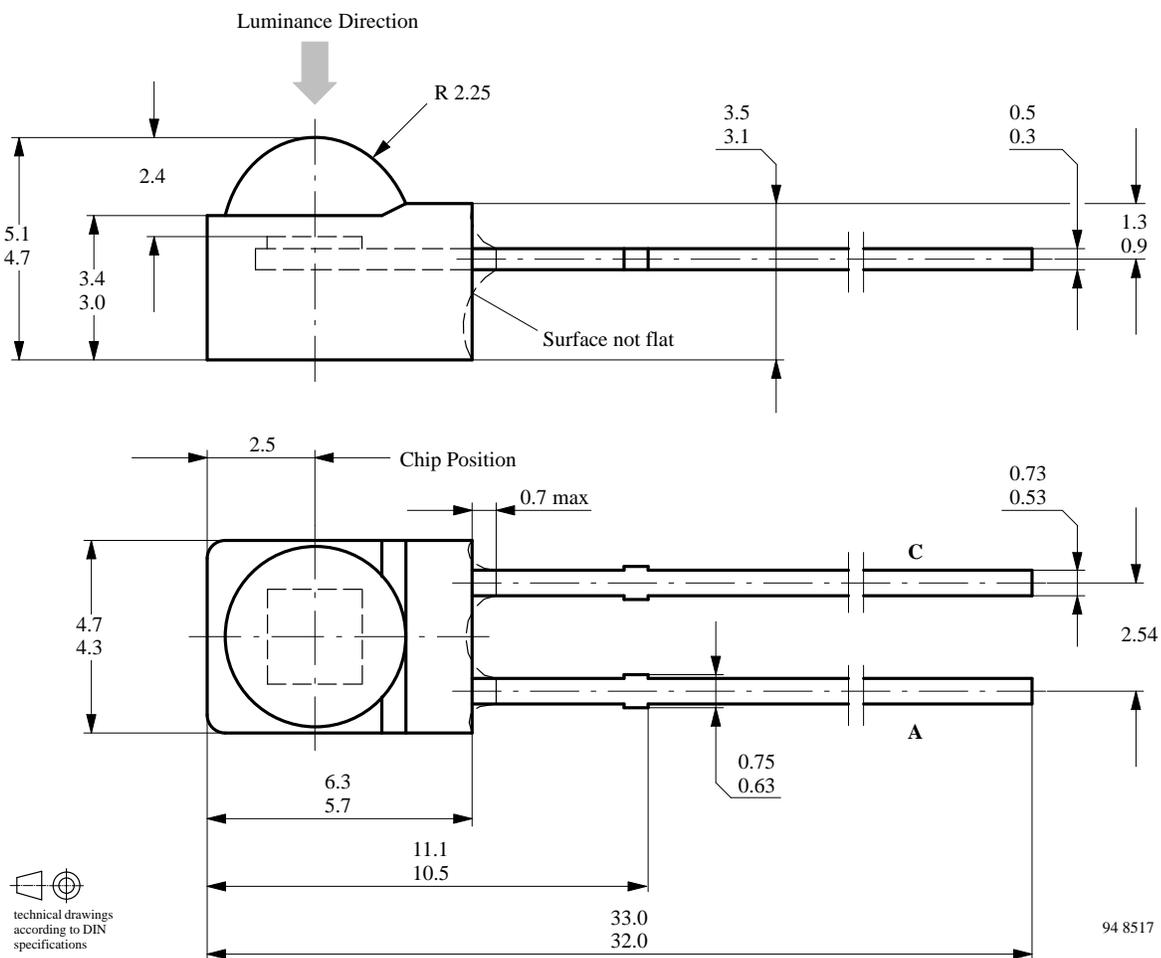
Figure 6 : Relative Spectral Sensitivity vs. Wavelength



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Figure 7 : Relative Radiant Sensitivity vs. Angular Displacement

Dimensions in mm



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We reserve the right to make changes to improve technical design without further notice.

Parameters can vary in different applications. All operating parameters must be validated for each customer application by the customer. Should the buyer use TEMIC products for any unintended or unauthorized application, the buyer shall indemnify TEMIC against all claims, costs, damages, and expenses, arising out of, directly or indirectly, any claim of personal damage, injury or death associated with such unintended or unauthorized use.

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